

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number	10800409
Filing Date	2004-03-11
First Named Inventor	Wu et al.
Art Unit	1762
Examiner Name	Chen, B.
Attorney Docket Number	NOVLP098/NVLS-2907

U.S.PATENTS						Remove
Examiner Initial*	Cite No	Patent Number	Kind Code ¹	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
/BC/	1	6662631		2003-12-16	Baklanov, et al.	
/BC/	2	7098149		2006-08-29	Lukas, et al.	

If you wish to add additional U.S. Patent citation information please click the Add button.

Add

U.S.PATENT APPLICATION PUBLICATIONS

Remove

Examiner Initial*	Cite No	Publication Number	Kind Code ¹	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear
/BC/	1	20030224156		2003-12-14	Kirner et al.	
	2	20030111263		2003-06-19	Fornof, et al.	
	3	20020132496		2002-09-19	Ball et al.	
/BC/	4	20060145305		2006-07-06	Boyanov et al.	

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number		10800409
Filing Date		2004-03-11
First Named Inventor	Wu et al.	
Art Unit	1762	
Examiner Name	Chen, B.	
Attorney Docket Number	NOVLP098/NVLS-2907	

/BC/	5	20060040507		2006-02-23	Mak et al.	
	6	20050230834		2005-10-20	Schmitt et al.	
	7	20060105566		2006-05-18	Waldfried et al.	
	8	20040018717		2004-01-29	Fornof et al.	
	9	20040213911		2004-10-28	Misawa et al.	
	10	20040249006		2004-12-09	Gleason et al.	
	11	20050095840		2005-05-05	Bhanap et al.	
/BC/	12	20060178006		2006-08-10	Xu et al.	

If you wish to add additional U.S. Published Application citation information please click the Add button

FOREIGN PATENT DOCUMENTS

Examiner Initial*	Cite No	Foreign Document Number ³	Country Code ²	Kind Code ⁴	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines where Relevant Passages or Relevant Figures Appear	T ⁵
/BC/	1	WO 03/052794 A2	WO		2003-06-26	AVANZINO et al.		<input type="checkbox"/>

If you wish to add additional Foreign Patent Document citation information please click the Add button

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number	10800409
Filing Date	2004-03-11
First Named Inventor	Wu et al.
Art Unit	1762
Examiner Name	Chen, B.
Attorney Docket Number	NOVLP098/NVLS-2907

NON-PATENT LITERATURE DOCUMENTS

Remove

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc), date, pages(s), volume-issue number(s), publisher, city and/or country where published.	T ⁵
/BC/	1	U.S. Office Action mailed November 30, 2006, from U.S Application No. 10/927,777 [Atty Dkt No. NOVLP106/NVLS-2930]	<input type="checkbox"/>
	2	U.S. Office Action mailed March 28, 2007, from U.S Application No. 10/820,525 [Atty Dkt No. NOVLP091/NVLS-2889]	<input type="checkbox"/>
	3	U.S. Office Action mailed January 24, 2007, from U.S Application No. 10/789,103 [Atty Dkt No. NOVLP094/NVLS-2919]	<input type="checkbox"/>
	4	U.S. Office Action mailed June 21, 2007, from U.S Application No. 10/789,103 [Atty Dkt No. NOVLP094/NVLS-2919]	<input type="checkbox"/>
	5	Niu et al., "Methods for Improving the Cracking Resistance of Low-K Dielectric Materials," Novellus Systems, Inc., Appl. No. 11/376,510, filed March 14, 2006, pages 1-28. [NOVLP099D1/NVLS-2896D1]	<input type="checkbox"/>
	6	U.S. Office Action dated May 22, 2007, from U.S. Application No. 11/376,510 [Atty Dkt: NOVLP099D1/NVLS-2896D1]	<input type="checkbox"/>
	7	U.S. Notice of Allowance and Fee Due mailed April 9, 2007, from U.S. Application No. 10/927,777. [NOVLP106/NVLS-2930]	<input type="checkbox"/>
	8	Allowed Claims from U.S. Application No. 10/927,777. [NOVLP106/NVLS-2930]	<input type="checkbox"/>
/BC/	9	U.S. Final Office Action mailed April 3, 2007, from U.S Application No. 10/941,502 [Atty Dkt No. NOVLP107/NVLS-2932]	<input type="checkbox"/>

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**
(Not for submission under 37 CFR 1.99)

Application Number		10800409
Filing Date		2004-03-11
First Named Inventor	Wu et al.	
Art Unit	1762	
Examiner Name	Chen, B.	
Attorney Docket Number	NOVLP098/NVLS-2907	

/BC/	10	U.S. Notice of Allowance and Fee Due mailed December 20, 2005, from U.S. Application No. 10/860,340. [NOVLP099/NVLS-2896]	<input type="checkbox"/>
	11	Wu et al., "PECVD Methods for Producing Ultra Low-K Dielectric Films Using UV Treatment," Novellus Systems, Inc., Appl. No. 11/608,056, filed December 7, 2006, pages 1-34. [NOVLP196/NVLS-3238]	<input type="checkbox"/>
/BC/	12	Wu et al., "Methods for Improving Performance of ODC Films with Dielectric Constant < 4.0," Novellus Systems, Inc., Appl. No. 11/693,661, filed March 29, 2007, pages 1-46. [NOVLP200/NVLS-3269]	<input type="checkbox"/>

If you wish to add additional non-patent literature document citation information please click the Add button

EXAMINER SIGNATURE

Examiner Signature	/Bret Chen/	Date Considered	09/15/2007
--------------------	-------------	-----------------	------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through a citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ See Kind Codes of USPTO Patent Documents at www.USPTO.GOV or MPEP 901.04. ² Enter office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁵ Applicant is to place a check mark here if English language translation is attached.